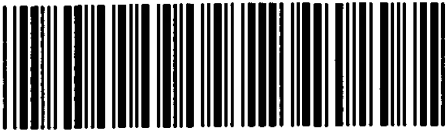


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	09/927,155	SAKAGUCHI ET AL.	
	Examiner	Art Unit	
	James J. Debrow	2176	

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
searched NPL in STIC database (see searched notes)	3/24/2006	JD